

## F-Probe™ – Ultra Low Leakage ‘Parametric’ Probe Card Specification

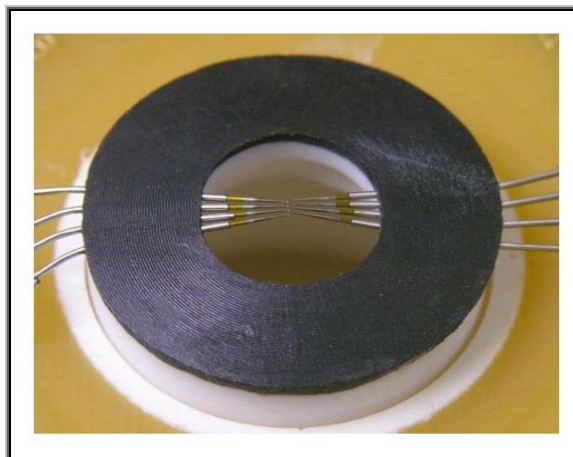
*ProbeLogic utilizes the latest State-of-the-Art Technology and Equipment to engineer, design, and manufacture high quality and “100% Tested” probe cards. ProbeLogic has the shortest turn-times and the most cost effective test solutions in the industry.*



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### Devices

Any Type	Parametric or E-Test Applications
Pad Configuration	Single or Dual In-line (up to 48)
Pad Pitch/Size	Pad Pitch: $\geq 60\mu$ Pad Width: $\geq 40\mu$ Length: $\geq 40\mu$
Pad Material	Aluminum, Gold, Copper (or Industry Standard)
Leakage	Coaxial Probe - $> 1fA/V @ 25C$

### Ring Assembly

Probe Ring	Custom Ceramic
Probe Material	Tungsten or Rhenium Tungsten
Testing Temperature	25°C to 120°C
Probe Diameter	8 mils
Tip Diameter	0.5 mils to 5 mils
Tip Shape	Flat or Radius
Tip Length	7 mils (or Build to Customer Spec.)
Contact Resistance	$< 2.0$ ohms
Alignment	$\pm 0.20$ mils
Planarity	$\pm 0.20$ mils
Contact Force	1-3 G/mils O.D.
Probe Depth	100 mils to 400 mils (Measured from bottom of PCB)

### PCB/Components

PCB Material	Polyimide
PCB Design	Standard ‘Generic’ or Custom
ATE Type	Parametric – Keithley, Verigy